



**ISO 11452-3**

**Road vehicles — Component test methods for electrical disturbances from narrowband radiated electromagnetic energy —**

**Part 3:  
Transverse electromagnetic (TEM) cell**

*Véhicules routiers — Méthodes d'essai d'un équipement soumis à des perturbations électriques par rayonnement d'énergie électromagnétique en bande étroite —*

*Partie 3: Cellule électromagnétique transverse (TEM)*

**Fourth edition  
2024-05**

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Published in Switzerland

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This document was prepared by Technical Committee ISO/TC 22, *Road vehicles*, Subcommittee SC 32, *Electrical and electronic components and general system aspects*.

This fourth edition cancels and replaces the third edition (ISO 11452-3:2016), of which it constitutes a minor revision. The changes are as follows:

- [Formula \(1\)](#) in [6.2.2](#) was modified.

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Immunity measurements of complete road vehicles are generally able to be carried out only by the vehicle manufacturer, owing to, for example, high costs of absorber-lined shielded enclosures, the desire to preserve the secrecy of prototypes or a large number of different vehicle models.

For research, development and quality control, a laboratory measuring method can be used by both vehicle manufacturers and equipment suppliers to test electronic components.

The TEM cell method has the major advantage of not radiating energy into the surrounding environment. The method can be used for testing either the immunity of a component with the field coupling to the wiring harness or the immunity of the component alone with minimum exposure to the wiring harness.